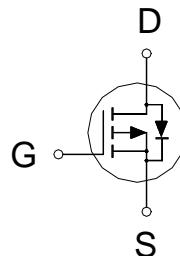


**P-Channel Logic Level Enhancement Mode Field Effect Transistor**

**Product Summary:**

BV <sub>DSS</sub>	-20V
R <sub>DSON</sub> (MAX.)	21mΩ
I <sub>D</sub>	-18A



Pb-Free Lead Plating & Halogen Free



**ABSOLUTE MAXIMUM RATINGS (T<sub>A</sub> = 25 °C Unless Otherwise Noted)**

PARAMETERS/TEST CONDITIONS		SYMBOL	LIMITS	UNIT
Gate-Source Voltage		V <sub>GS</sub>	±12	V
Continuous Drain Current	T <sub>C</sub> = 25 °C	I <sub>D</sub>	-18	A
	T <sub>A</sub> = 25 °C		-9	
	T <sub>C</sub> = 100 °C		-12	
Pulsed Drain Current <sup>1</sup>		I <sub>DM</sub>	-56	
Power Dissipation	T <sub>C</sub> = 25 °C	P <sub>D</sub>	21	W
	T <sub>C</sub> = 100 °C		8.3	
Power Dissipation	T <sub>A</sub> = 25 °C	P <sub>D</sub>	2.5	W
	T <sub>A</sub> = 70 °C		1.6	
Operating Junction & Storage Temperature Range		T <sub>j</sub> , T <sub>stg</sub>	-55 to 150	°C

**THERMAL RESISTANCE RATINGS**

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNIT
Junction-to-Case	R <sub>θJC</sub>		6	°C / W
Junction-to-Ambient <sup>3</sup>	R <sub>θJA</sub>		50	

<sup>1</sup>Pulse width limited by maximum junction temperature.

<sup>2</sup>Duty cycle ≤ 1%

<sup>3</sup>50°C / W when mounted on a 1 in<sup>2</sup> pad of 2 oz copper.

ELECTRICAL CHARACTERISTICS ( $T_J = 25^\circ\text{C}$ , Unless Otherwise Noted)

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
<b>STATIC</b>						
Drain-Source Breakdown Voltage	$V_{(\text{BR})\text{DSS}}$	$V_{GS} = 0V, I_D = -250\mu\text{A}$	-20			V
Gate Threshold Voltage	$V_{GS(\text{th})}$	$V_{DS} = V_{GS}, I_D = -250\mu\text{A}$	-0.3	-0.75	-1.2	
Gate-Body Leakage	$I_{GSS}$	$V_{DS} = 0V, V_{GS} = \pm 12V$			$\pm 100$	nA
Zero Gate Voltage Drain Current	$I_{DSS}$	$V_{DS} = -16V, V_{GS} = 0V$			-1	$\mu\text{A}$
		$V_{DS} = -16V, V_{GS} = 0V, T_J = 125^\circ\text{C}$			-10	
On-State Drain Current <sup>1</sup>	$I_{D(\text{ON})}$	$V_{DS} = -5V, V_{GS} = -4.5V$	-18			A
Drain-Source On-State Resistance <sup>1</sup>	$R_{DS(\text{ON})}$	$V_{GS} = -4.5V, I_D = -9A$		16	21	$\text{m}\Omega$
		$V_{GS} = -2.5V, I_D = -5A$		19	25	
		$V_{GS} = -1.8V, I_D = -3A$		26	40	
Forward Transconductance <sup>1</sup>	$g_{fs}$	$V_{DS} = -5V, I_D = -9A$		22		S
<b>DYNAMIC</b>						
Input Capacitance	$C_{iss}$	$V_{GS} = 0V, V_{DS} = -10V, f = 1\text{MHz}$		3100		$\text{pF}$
Output Capacitance	$C_{oss}$			460		
Reverse Transfer Capacitance	$C_{rss}$			413		
Total Gate Charge <sup>1,2</sup>	$Q_g(V_{GS}=-4.5V)$	$V_{DS} = -10V, V_{GS} = -4.5V, I_D = -9A$		25.5		$\text{nC}$
	$Q_g(V_{GS}=-2.5V)$			15		
Gate-Source Charge <sup>1,2</sup>	$Q_{gs}$			2.2		
Gate-Drain Charge <sup>1,2</sup>	$Q_{gd}$			5.7		
Turn-On Delay Time <sup>1,2</sup>	$t_{d(\text{on})}$	$V_{DS} = -10V, I_D = -1A, V_{GS} = -4.5V, R_{GS} = 6\Omega$		20		$\text{nS}$
Rise Time <sup>1,2</sup>	$t_r$			50		
Turn-Off Delay Time <sup>1,2</sup>	$t_{d(\text{off})}$			95		
Fall Time <sup>1,2</sup>	$t_f$			60		
<b>SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS (<math>T_c = 25^\circ\text{C}</math>)</b>						
Continuous Current	$I_S$				-18	A
Pulsed Current <sup>3</sup>	$I_{SM}$				-72	
Forward Voltage <sup>1</sup>	$V_{SD}$	$I_F = -9A, V_{GS} = 0V$			-1.2	V

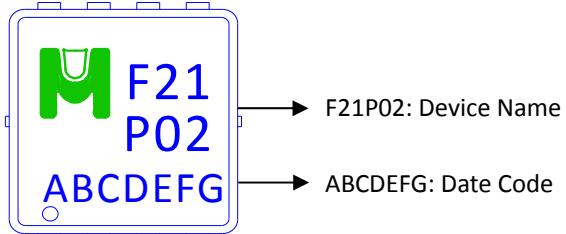
<sup>1</sup>Pulse test : Pulse Width  $\leq 300 \mu\text{sec}$ , Duty Cycle  $\leq 2\%$ .

<sup>2</sup>Independent of operating temperature.

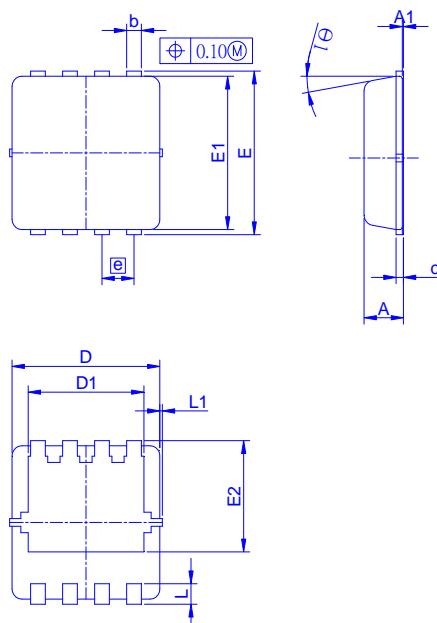
<sup>3</sup>Pulse width limited by maximum junction temperature.

### Ordering & Marking Information:

Device Name: EMF21P02V for EDFN 3 x 3



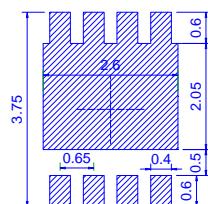
Outline Drawing



Dimension in mm

Dimension	A	A1	b	c	D	D1	E	E1	E2	e	L	L1	$\theta_1$
Min.	0.65	0	0.20	0.10	2.90	2.15	3.10	2.90	1.53	0.55	0.25	-	0°
Typ.	0.75	-	0.30	0.15	3.00	2.45	3.20	3.00	1.97	0.65	0.40	0.075	10°
Max.	0.90	0.05	0.40	0.25	3.30	2.74	3.50	3.30	2.59	0.75	0.60	0.150	14°

### Recommended minimum pads



### TYPICAL CHARACTERISTICS

